Form PTO 1449		U.S. DEPARTMENT	OF COMMERCE	ATTY DOCKET NO.	SERIAL NO.			
(Modified)		PATENT AND TRAI	DEMARK OFFICE	246722US2SRD DIV		New DIV Application		
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	AZ Additional References sheet(s) attached						erences sheet(s) attached	
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*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								